

CHARACTERISATION TECHNIQUES

Surface Science and Chemical Analyses

- Auger Electron Spectrometer (AES)
- Contact Angle Goniometer
- Ellipsometer
- Gas Chromatography Mass Spectrometer (GCMS)
- Inductively-Coupled Plasma Mass Spectrometer (ICPMS)
- Nuclear Magnetic Resonance (NMR)
- Optical Surface Analyzer (OSA)
- Time-of-flight Secondary Ion Mass Spectrometer (TOFSIMS)
- X-ray Photoelectron Spectrometer (XPS)

Thermal and Spectroscopy

- Brunauer–Emmett–Teller Analyzer (BET)
- Dynamic Mechanical Analyzer (DMA)
- Differential Scanning Calorimeter (DSC)
- Carbon-Hydrogen-Nitrogen-Sulfur-Oxygen Analyzer (CHNSO)
- Fourier Transform Infrared Spectrometer (FTIR)
- Heat Flow Meter (HFM)
- Laser Flash Apparatus (LFA)
- Raman Spectrometer
- Thermogravimetric Analyzer (TGA)
- Thermogravimetric Mass Spectrometer (TGMS)
- X-ray Fluorescence (XRF)

Microscopy and Physical Properties

- Atomic/Magnetic Force Microscope (AFM/MFM)
- Alternating Gradient Magnetometer (AGM)
- Field Effect Scanning Electron Microscope (FESEM/EDS)
- Focused Ion Beam (FIB)
- Hall Measurement System
- Nano-indenter
- Superconducting Quantum Interference Device (SQUID)
- Transmission Electron Microscope (TEM/EDS/EELS)
- Vibrating Sample Magnetometer (VSM)
- X-ray Diffractometer / X-ray Reflectivity (XRD/XRR)

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